

## UTM6006

Power MOSFET

## 6.3A, 60V N-CHANNEL FAST SWITCHING MOSFET

## ■ DESCRIPTION

The UTC **UTM6006** is an N-Channel MOSFET, it uses UTC's advanced technology to provide customers with a minimum on-state resistance, high switching speed and low gate charge.

The UTC **UTM6006** is suitable for application in networking AC-DC power system and LCD/LED back light, etc.

## ■ FEATURES

- \*  $R_{DS(ON)} \leq 18 \text{ m}\Omega$  @  $V_{GS}=10\text{V}$ ,  $I_D=6.0\text{A}$

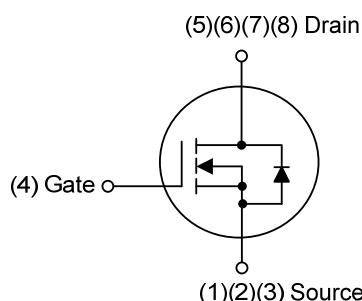
- $R_{DS(ON)} \leq 20 \text{ m}\Omega$  @  $V_{GS}=4.5\text{V}$ ,  $I_D=4.0\text{A}$

- \* Low gate charge

- \* Excellent CdV/dt effect decline

- \* High switching speed

## ■ SYMBOL

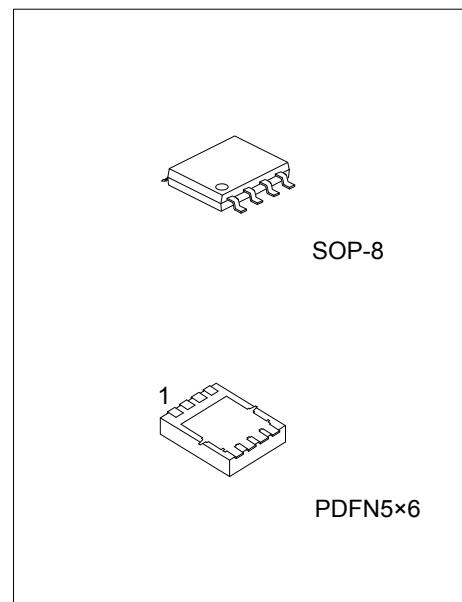


## ■ ORDERING INFORMATION

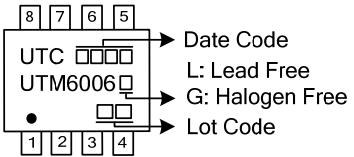
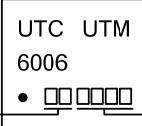
Ordering Number		Package	Pin Assignment								Packing
Lead Free	Halogen Free		1	2	3	4	5	6	7	8	
UTM6006L-S08-R	UTM6006G-S08-R	SOP-8	S	S	S	G	D	D	D	D	Tape Reel
UTM6006L-P5060-R	UTM6006G-P5060-R	PDFN5×6	S	S	S	G	D	D	D	D	Tape Reel

Note: Pin Assignment: G: Gate D: Drain S: Source

UTM6006G-S08-R	(1)Packing Type (2)Package Type (3)Green Package	(1) R: Tape Reel (2) S08: SOP-8, P5060: PDFN5×6 (3) G: Halogen Free and Lead Free, L: Lead Free
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### ■ MARKING

SOP-8	PDFN5×6
 <p>8 7 6 5 UTC □□□ UTM6006□ • □□ 1 2 3 4</p> <p>Date Code L: Lead Free G: Halogen Free Lot Code</p>	 <p>UTC UTM 6006 • □□□□□</p> <p>Lot Code ← Date Code →</p>

■ ABSOLUTE MAXIMUM RATINGS

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V <sub>DSS</sub>	60	V
Gate-Source Voltage		V <sub>GSS</sub>	±20	V
Drain Current	Continuous	T <sub>A</sub> =25°C	I <sub>D</sub>	6.3
	V <sub>GS</sub> @ 10V (Note 1)	T <sub>A</sub> =70°C		5.0
	Pulsed (Note 2)		I <sub>DM</sub>	32
Avalanche Current		I <sub>AS</sub>	28	A
Single Pulse Avalanche Energy (Note 3)		E <sub>AS</sub>	67	mJ
Power Dissipation (T <sub>A</sub> =25°C) (Note 4)	SOP-8	P <sub>D</sub>	1.5	W
	PDFN5×6		1.92	
Junction Temperature		T <sub>J</sub>	-55 ~ +150	°C
Storage Temperature Range		T <sub>STG</sub>	-55 ~ +150	°C

Note: Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

■ THERMAL DATA (Note 1)

PARAMETER		SYMBOL	RATINGS	UNIT
Junction to Ambient	SOP-8	θ <sub>JA</sub>	85	°C/W
	PDFN5×6		65	
Junction to Case	SOP-8	θ <sub>JC</sub>	24	°C/W
	PDFN5×6		12	

Notes: 1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.

2. The data tested by pulsed, pulse width ≤ 300μs, duty cycle ≤ 2%.

3. The EAS data shows Max. rating. The test condition is V<sub>DD</sub>=25V, V<sub>GS</sub>=10V, L=0.1mH, I<sub>AS</sub>=30A.

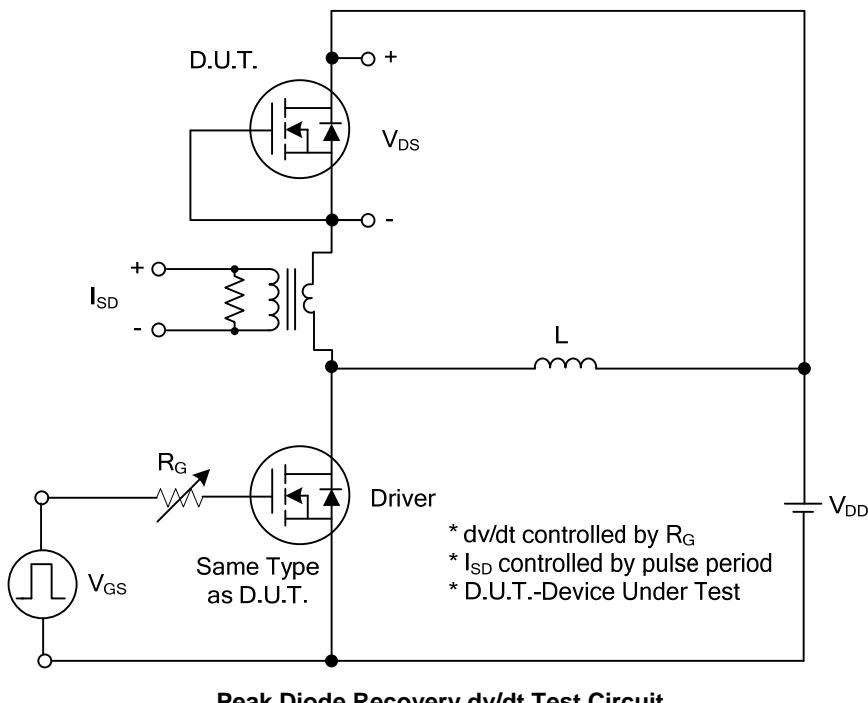
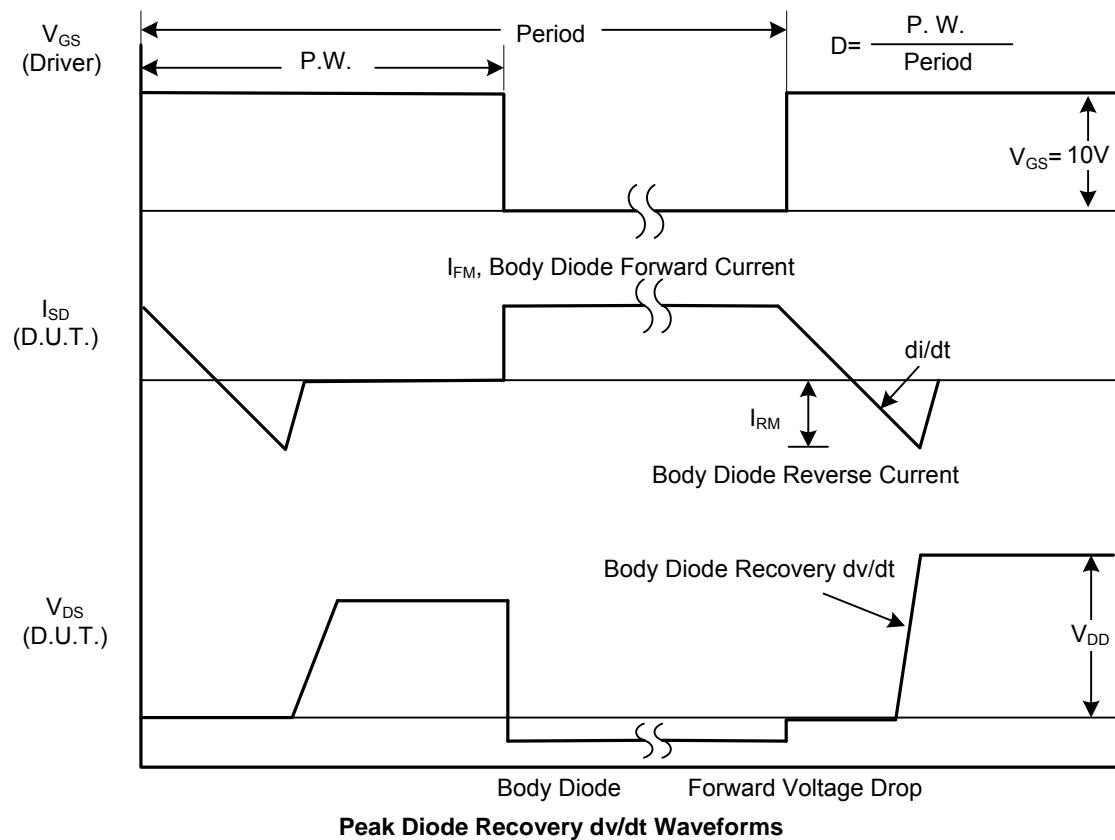
4. The power dissipation is limited by 150°C junction temperature.

■ ELECTRICAL CHARACTERISTICS ( $T_J=25^\circ\text{C}$ , unless otherwise noted)

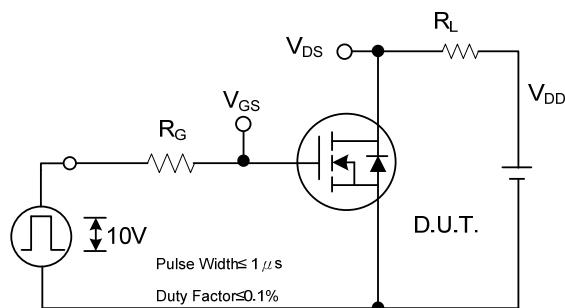
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
<b>OFF CHARACTERISTICS</b>						
Drain-Source Breakdown Voltage	$\text{BV}_{\text{DSS}}$	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	60			V
$\text{BV}_{\text{DSS}}$ Temperature Coefficient	$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	Reference to $25^\circ\text{C}$ , $I_D=1\text{mA}$		0.057		$\text{V}/^\circ\text{C}$
Drain-Source Leakage Current	$I_{\text{DSS}}$	$V_{DS}=48\text{V}, V_{GS}=0\text{V}, T_J=25^\circ\text{C}$		1		$\mu\text{A}$
		$V_{DS}=48\text{V}, V_{GS}=0\text{V}, T_J=55^\circ\text{C}$		5		$\mu\text{A}$
Gate-Source Leakage Current	Forward	$V_{GS}=+20\text{V}, V_{DS}=0\text{V}$		+100		nA
	Reverse	$V_{GS}=-20\text{V}, V_{DS}=0\text{V}$		-100		nA
<b>ON CHARACTERISTICS</b>						
Gate Threshold Voltage	$V_{GS(\text{TH})}$	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.2		2.5	V
$V_{GS(\text{TH})}$ Temperature Coefficient	$\Delta V_{GS(\text{TH})}$			-5.68		$\text{mV}/^\circ\text{C}$
Static Drain-Source On-State Resistance (Note 2)	$R_{DS(\text{ON})}$	$V_{GS}=10\text{V}, I_D=6.0\text{A}$		14	18	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=4.0\text{A}$		16	20	$\text{m}\Omega$
Forward Transconductance	$g_{FS}$	$V_{DS}=5\text{V}, I_D=6\text{A}$		40		S
<b>DYNAMIC PARAMETERS</b>						
Input Capacitance	$C_{ISS}$	$V_{GS}=0\text{V}, V_{DS}=25\text{V}, f=1.0\text{MHz}$		1070	1200	pF
Output Capacitance	$C_{OSS}$			200	220	pF
Reverse Transfer Capacitance	$C_{RSS}$			190	210	pF
<b>SWITCHING PARAMETERS (Note 2)</b>						
Total Gate Charge (4.5V)	$Q_G$	$V_{GS}=10\text{V}, V_{DS}=48\text{V}, I_D=1\text{A}$		290	310	nC
Gate to Source Charge	$Q_{GS}$			10.7	15	nC
Gate to Drain Charge	$Q_{GD}$			30	45	nC
Turn-ON Delay Time	$t_{D(\text{ON})}$	$V_{GS}=10\text{V}, V_{DD}=30\text{V}, R_G=3.3\Omega, I_D=2\text{A}$		55	70	ns
Rise Time	$t_R$			100	120	ns
Turn-OFF Delay Time	$t_{D(\text{OFF})}$			580	620	ns
Fall-Time	$t_F$			190	210	ns
<b>GUARANTEED AVALANCHE CHARACTERISTICS</b>						
Single Pulse Avalanche Energy (Note 5)	$E_{AS}$	$V_{DD}=25\text{V}, L=0.1\text{mH}, I_{AS}=15\text{A}$	19			mJ
<b>DIODE CHARACTERISTICS</b>						
Continuous Source Current (Note 1, 6)	$I_S$	$V_G=V_D=0\text{V}$ , Force Current			6.3	A
Pulsed Source Current (Note 2, 6)	$I_{SM}$				32	A
Diode Forward Voltage (Note 2)	$V_{SD}$	$V_{GS}=0\text{V}, I_S=6.3\text{A}, T_J=25^\circ\text{C}$			1	V
Reverse Recovery Time	$t_{rr}$	$I_F=6\text{A}, dI/dt=100\text{A}/\mu\text{s}, T_J=25^\circ\text{C}$		15		nS
Reverse Recovery Charge	$Q_{rr}$			10.4		nC

- Notes: 1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.  
 2. The data tested by pulsed, pulse width $\leq 300\mu\text{s}$ , duty cycle $\leq 2\%$ .  
 3. The EAS data shows Max. rating. The test condition is  $V_{DD}=25\text{V}, V_{GS}=10\text{V}, L=0.1\text{mH}, I_{AS}=30\text{A}$ .  
 4. The power dissipation is limited by  $150^\circ\text{C}$  junction temperature.  
 5. The Min. value is 100% EAS tested guarantee.  
 6. The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.

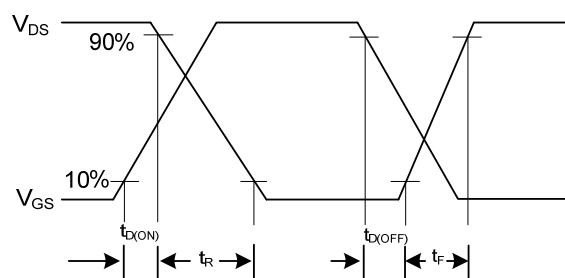
■ TEST CIRCUITS AND WAVEFORMS

Peak Diode Recovery  $dv/dt$  Test CircuitPeak Diode Recovery  $dv/dt$  Waveforms

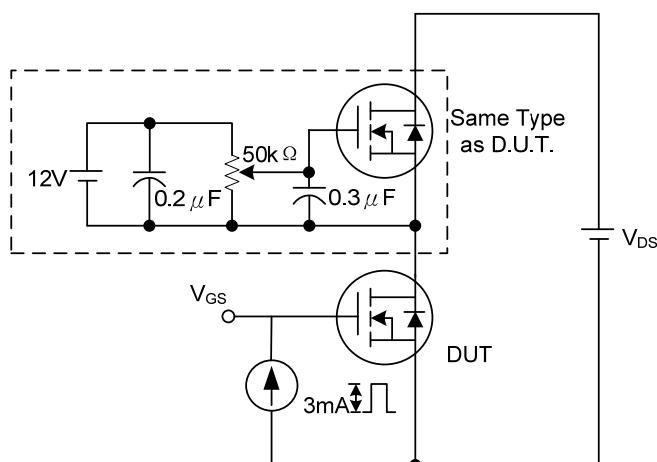
### ■ TEST CIRCUITS AND WAVEFORMS



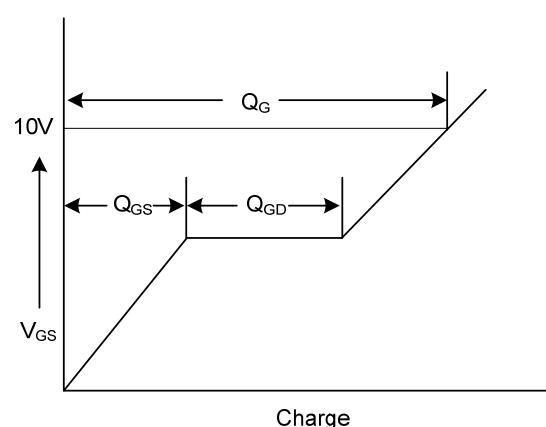
Switching Test Circuit



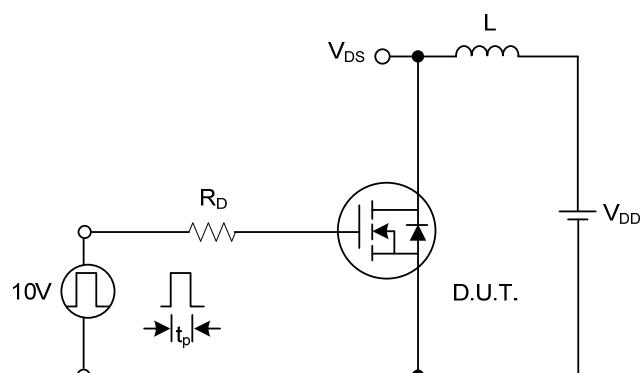
Switching Waveforms



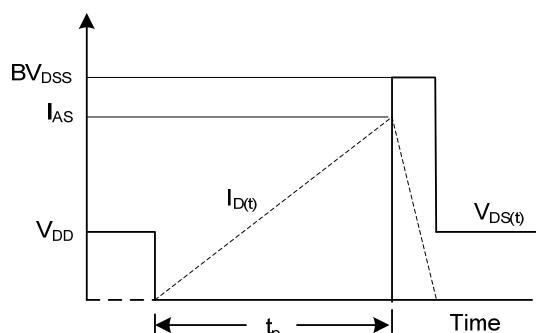
Gate Charge Test Circuit



Gate Charge Waveform

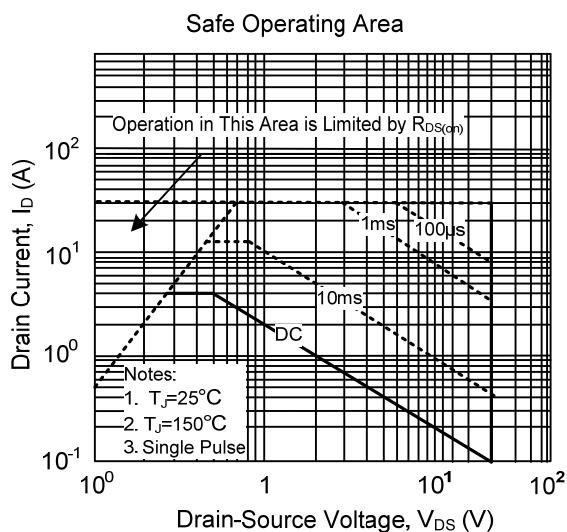
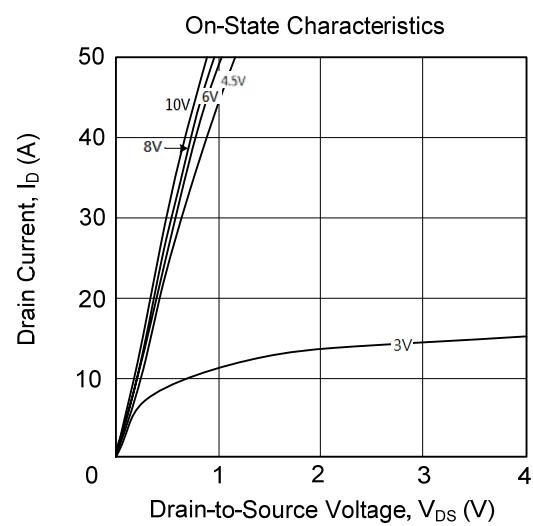
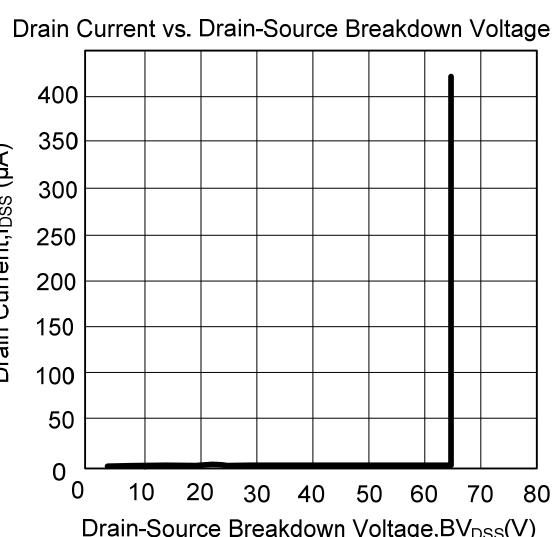
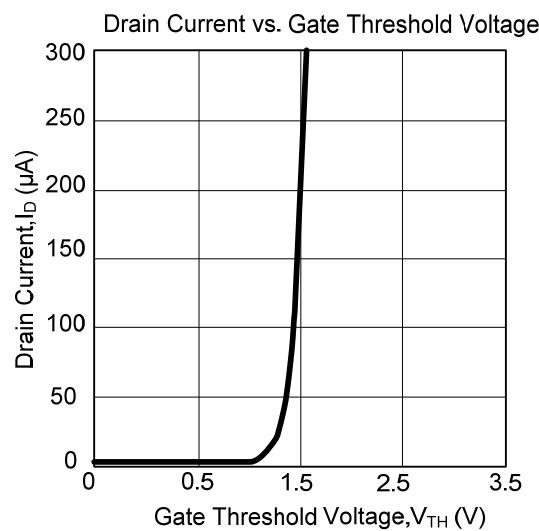
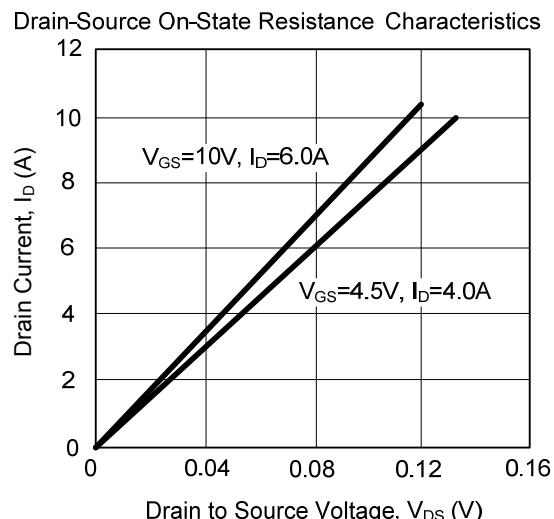
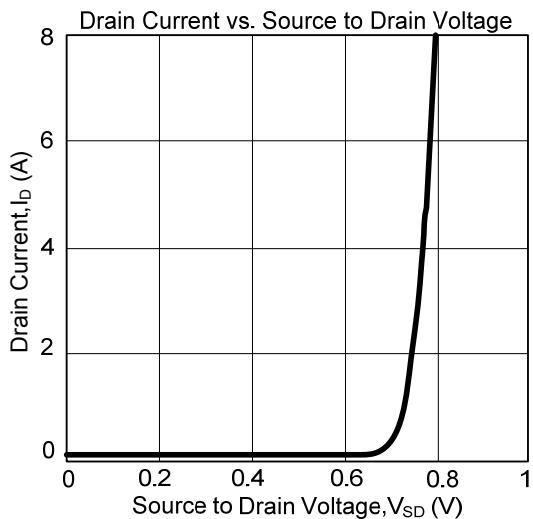


Unclamped Inductive Switching Test Circuit

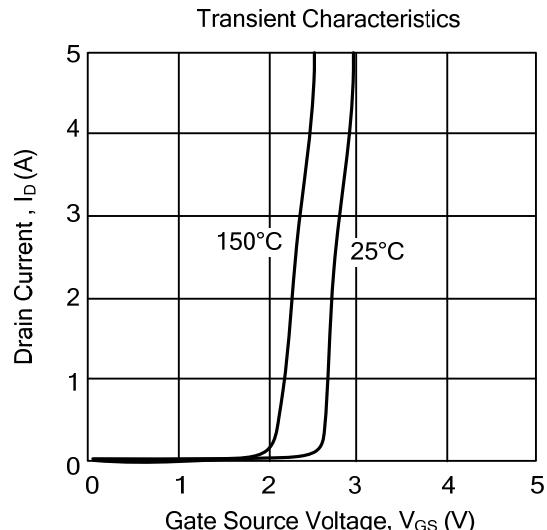
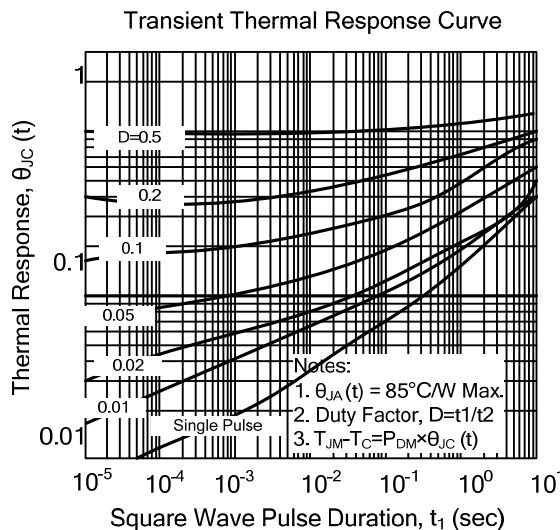


Unclamped Inductive Switching Waveforms

### ■ TYPICAL CHARACTERISTICS



■ TYPICAL CHARACTERISTICS (Cont.)



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